

MN100325-X REV 1B0

 Original Creation Date: 10/30/95
 Last Update Date: 05/07/04
 Last Major Revision Date: 08/21/96

HEX ECL-to-TTL TRANSLATOR
General Description

The 100325 is a hex translator for converting F100K logic level to TTL logic levels. Differential inputs allow each circuit to be used as an inverting, non-inverting or differential receiver. An internal reference voltage generator provides VBB for single-ended operation or for use in Schmitt trigger applications. All inputs have 50K ohms pull-down resistors; therefore, the outputs will go LOW when the inputs are left unconnected. When used in the differential mode, the inputs have a common mode rejection of +1V, making this device tolerant of ground offsets and transients between the signal source and the translator. The VEE and VTTL power may be applied in either order.

Industry Part Number

100325

Prime Die

F325

NS Part Numbers

 100325DMQB
 100325FMQB
 100325J-QMLV
 100325W-QMLV
 100325WFQMLV

Controlling Document

SEE FEATURES SECTION

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

| Subgrp | Description | Temp (°C) |
|--------|---------------------|------------|
| 1 | Static tests at | +25 |
| 2 | Static tests at | +125 |
| 3 | Static tests at | -55 |
| 4 | Dynamic tests at | +25 |
| 5 | Dynamic tests at | +125 |
| 6 | Dynamic tests at | -55 |
| 7 | Functional tests at | +25 |
| 8A | Functional tests at | +125 |
| 8B | Functional tests at | -55 |
| 9 | Switching tests at | +25 |
| 10 | Switching tests at | +125 |
| 11 | Switching tests at | -55 |

Features

- Pin/function compatible with 100125
- 50% power reduction of the 100125
- Differential inputs with built in offset
- 2000V ESD protection
- -4.2V to -5.7V operating range
- Available to industrial grade temperature range
- Available to MIL-STD-883

CONTROLLING DOCUMENTS:

| | |
|--------------|-----------------|
| 100325DMQB | 5962-9153101MXA |
| 100325FMQB | 5962-9153101MYA |
| 100325J-QMLV | 5962-9153101VXA |
| 100325W-QMLV | 5962-9153101VYA |
| 100325WFQMLV | 5962F9153101VYA |

(Absolute Maximum Ratings)

(Note 1)

| | |
|-----------------------------------|-----------------|
| Storage Temperature (Tstg) | -65 C to +150 C |
| Maximum Junction Temperature (Tj) | |
| Ceramic | +175 C |
| Plastic | +150 C |
| Vee Pin Potential to Ground Pin | -7.0V to +0.5V |
| Input Voltage (DC) | -0.5V to +6.0V |
| Output Current (DC Output HIGH) | -50mA |
| ESD (Note 2) | ≥ 2000V |
| VTTL Pin Potential to Ground Pin | -0.5V to +6.0V |

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Recommended Operating Conditions

| | |
|-----------------------|-----------------|
| Case Temperature (Tc) | |
| Commercial | 0 C to +85 C |
| Military | -55 C to +125 C |
| Industrial | -40 C to +85 C |
| Supply Voltage (Vee) | -5.7V to -4.2V |

Electrical Characteristics

DC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: Vee Range: -4.2V to -5.7V, VTTL RANGE:4.5V to 5.5V, Tc=-55c to +125c, VCC=GND

| SYMBOL | PARAMETER | CONDITIONS | NOTES | PIN-NAME | MIN | MAX | UNIT | SUB-GROUPS |
|--------|-----------------------------|--|---------|----------|-------|-------|------|------------|
| IIH | Input HIGH Current | VEE=-5.7V, VTTL=5.0V, VM=-0.87V | 1, 3 | INPUTS | | 350 | uA | 1, 2 |
| | | | 1, 3 | INPUTS | | 500 | uA | 3 |
| IIL | Input Low Current | VEE=-4.2V, VTTL=5.0V, VM=-1.83V | 1, 3 | INPUTS | 0.5 | | uA | 1, 2, 3 |
| VOH | Output HIGH Voltage | VEE=-4.2V/-5.7V, VTTL=4.5V, VIH=-0.87V, VIL=-1.83V, IOH=-2.0mA | 1, 3 | OUTPUTS | 2.5 | | V | 1, 2 |
| | | | 1, 3 | OUTPUTS | 2.4 | | V | 3 |
| VOL | Output LOW Voltage | Vee=-4.2V/-5.7V, VTTL=4.5V, VIH=-0.87V, VIL=-1.83V, IOL=20.0mA | 1, 3 | OUTPUTS | | 0.5 | V | 1, 2, 3 |
| IOS | Short-Circuit Current | VEE=-4.5V, VTTL=5.5V, VM=0.0V | 1, 3 | OUTPUTS | -60 | -150 | mA | 1, 2, 3 |
| ICEX | Output HIGH Leakage Current | VEE=-4.5V, VTTL=5.5V, VM=5.5V | 1, 3 | OUTPUTS | | 250 | uA | 1, 2, 3 |
| VBBX | Output Reference Voltage | VEE=-4.5V, VTTL=5.0V, IM=-3uA | 1, 3 | VBB | | -1260 | mV | 1, 2, 3 |
| VBBN | Output Reference Voltage | VEE=-5.7V, VTTL=5.0V, IM=-2.1mA | 1, 3 | VBB | -1380 | | mV | 1, 2 |
| | | VEE= -5.7V, VTTL=5.0V, IM=-3mA | 1, 3 | VBB | -1396 | | mV | 3 |
| VIH | Input HIGH Voltage | OTHER INPUT AT VBB | 1, 3, 7 | INPUTS | -1165 | -870 | mV | 1, 2, 3 |
| VIL | Input LOW Voltage | OTHER INPUT AT VBB | 1, 3, 7 | INPUTS | -1830 | -1475 | mV | 1, 2, 3 |
| VCM | Common Mode Voltage | VEE= -4.2/-5.7V, VTTL=4.5V | 1, 3, 7 | INPUTS | -2000 | -500 | mV | 1, 2, 3 |
| VDIF | Input Voltage Differential | VEE= -4.2/-5.7V, VTTL=4.5V | 1, 3, 7 | INPUTS | 150 | | mV | 1, 2, 3 |
| IEE | Power Supply Current | VEE=-4.2/-5.7V, VTTL=5.0V, VIN=VBB | 1, 3 | VEE | -35 | -12 | mA | 1, 2, 3 |
| ITTL | Power Supply Current | VEE=-4.5V, VTTL=5.5V, VIN=VBB | 1, 3 | VTTL | | 65 | mA | 1, 2, 3 |

Electrical Characteristics

AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
 AC: Vee Range: -4.2V to -5.7V, VTTL Range: 4.5V to 5.5V, VCC=GND, LOADING: 50 pF/500 Ohms

| SYMBOL | PARAMETER | CONDITIONS | NOTES | PIN-NAME | MIN | MAX | UNIT | SUB-GROUPS |
|-----------|-------------------|--|-------|----------|-----|-----|------|------------|
| tpLH/tpHL | Propagation Delay | VEE=-4.2/-5.7V, VTTL=4.5/5.5V, VCC=GND | 2, 4 | Dn to Qn | 1.6 | 4.7 | ns | 9 |
| | | | 2, 4 | Dn to Qn | 1.7 | 5.7 | ns | 10 |
| | | | 2, 4 | Dn to Qn | 1.5 | 5.0 | ns | 11 |
| tTLH/tTHL | Transistion Time | VEE=-4.2/-5.7V, VTTL=4.5/5.5V, VCC=GND | 6 | Qn | 0.5 | 2.5 | ns | 9, 10 |
| | | | 6 | Qn | 0.5 | 3.0 | ns | 11 |

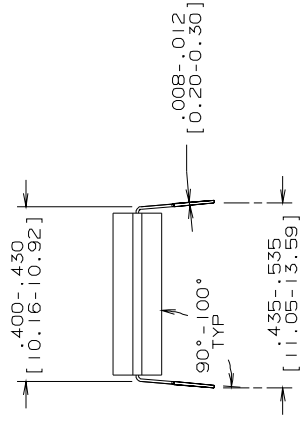
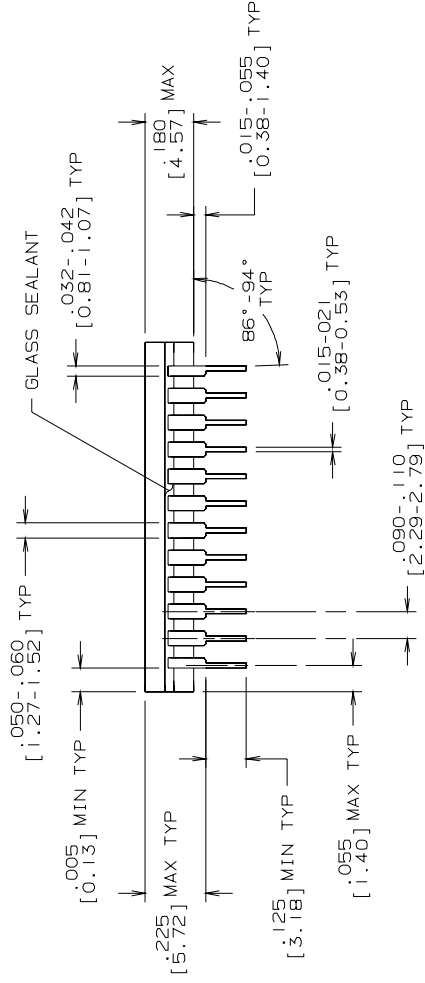
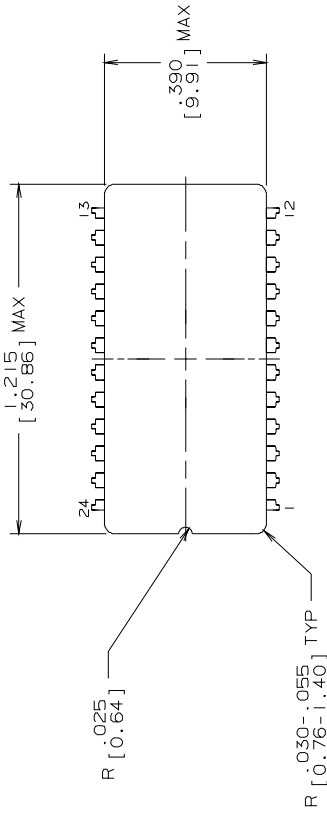
- Note 1: Screen tested 100% on each device at -55 C, +25 C and +125 C temp., subgroups 1, 2, 3, 7 & 8.
- Note 2: For QB devices, screen tested 100% on each device at +25C temperature only, subgroup A9. For QMLV devices, screen tested 100% on each device at +25C, +125C & -55C temperature, subgroup A9, 10 & 11.
- Note 3: Sample tested (Method 5005, Table 1) on each MFG. lot at +25 C, +125 C & -55 C temp., subgroups A1, 2, 3, 7 & 8.
- Note 4: Sample tested (Method 5005, Table 1) on each MFG. lot at +25 C, subgroup A9, and at +125 C & -55 C temp., subgroups A10 & 11.
- Note 5: Sample tested (Method 5005, Table 1) on each MFG. lot at +25 C temp. only, subgroup A9.
- Note 6: Not tested at +25 C, +125 C & -55 C temp. (DESIGN CHARACTERIZATION DATA).
- Note 7: Guaranteed by applying specified input condition and testing VOH/VOL.

Graphics and Diagrams

| GRAPHICS# | DESCRIPTION |
|-----------|--|
| J24ERJ | CERDIP (J), 24LD, .400 CENTERS (P/P DWG) |
| P000054A | CERDIP (J), 24LD .400 CENTERS (PIN OUT) |
| P000055A | CERPACK, QUAD, 24 LEAD (PIN OUT) |
| W24BRE | CERPACK, QUAD, 24 LEAD (P/P DWG) |

See attached graphics following this page.

| REVISIONS | | | |
|-----------|-------------------|--------|---------------|
| LTR | DESCRIPTION | E.C.N. | DATE |
| J | REVISE AND REDRAW | 09044 | 03/05/92 DEG/ |

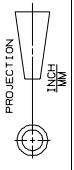


MIL/AERO MIL-M-38510 CONFIGURATION CONTROL CONFIGURATION CONTROL

| CONTROLLING DIMENSION: INCH | |
|--|----------------|
| APPROVALS | DATE |
| DRAWN D.E. GRADY | 03/05/92 |
| DTG. CHK. | |
| ENGR. CHK. | |
| APPROVAL | |
| NATIONAL SEMICONDUCTOR CORPORATION 2900 Semiconductor Drive, Santa Clara, CA 95052-8090 | |
| CERDIP (J), 24 LEAD, .400 CENTERS | |
| SCALE | DRAWING NUMBER |
| N/A | C MKT-J24E |
| FORMERLY: | SHEET 1 OF 1 |

NOTES: UNLESS OTHERWISE SPECIFIED

- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-M-38510 TO A MINIMUM THICKNESS OF 200 MICRONS/5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE.
- LEAD THICKNESS MAY BE INCREASED BY .003 [0.08] MAXIMUM AFTER LEAD FINISH APPLIED.
- BUMPERS ARE AVAILABLE ON CERTAIN PRODUCTS. BUMPERS WILL ADD .040 [1.02] MAX TO THE LENGTH OF THE PACKAGE.
- NO JEDEC REGISTRATION AS OF 2/17/92.



Revision History

| Rev | ECN # | Rel Date | Originator | Changes |
|-----|----------|----------|-------------|---|
| 1B0 | M0004382 | 05/07/04 | Rose Malone | Update MDS: MN100325-X, Rev. 1A0 to 1B0. Added NSID 100325WFQMLV to Main Table and to Features Section. |

National Semiconductor was acquired by Texas Instruments.

http://www.ti.com/corp/docs/investor_relations/pr_09_23_2011_national_semiconductor.html

This file is the datasheet for the following electronic components:

5962-9153101MYA - <http://www.ti.com/product/5962-9153101mya?HQS=TI-null-null-dscatalog-df-pf-null-wwe>

5962-9153101MXA - <http://www.ti.com/product/5962-9153101mxa?HQS=TI-null-null-dscatalog-df-pf-null-wwe>

5962-9153101VXA - <http://www.ti.com/product/5962-9153101vxa?HQS=TI-null-null-dscatalog-df-pf-null-wwe>

5962-9153101VYA - <http://www.ti.com/product/5962-9153101vya?HQS=TI-null-null-dscatalog-df-pf-null-wwe>

5962F9153101VYA - <http://www.ti.com/product/5962f9153101vya?HQS=TI-null-null-dscatalog-df-pf-null-wwe>



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